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APPLICATION NO.	FILING DATE	FIRST NAMED INVENTOR	ATTORNEY DOCKET NO.	CONFIRMATION NO.
09/942,153	08/29/2001	Masayoshi Shiga	P/1250-214	6816
2352	7590 . 06/19/2003			
OSTROLENK FABER GERB & SOFFEN			EXAMINER	
	JE OF THE AMERICAS , NY 100368403	MOORE, KARLA A		
			ART UNIT	PAPER NUMBER
			1763	
	•		DATE MAILED: 06/19/2003	7

Please find below and/or attached an Office communication concerning this application or proceeding.

		Application N .	Applicant(s)	
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•	Office Action Summary	09/942,153	SHIGA ET AL.	
	Office Action Summary	Examiner	Art Unit	
	The MAH INC DATE of this communication on	Karla Moore	1763	a del rano
Period f	The MAILING DATE of this communication apr Reply	pears on the cover s	neet with the correspondence	address
THE - Exte after - If the - If NC - Failu - Any	ORTENED STATUTORY PERIOD FOR REPI MAILING DATE OF THIS COMMUNICATION. nsions of time may be available under the provisions of 37 CFR 1 SIX (6) MONTHS from the mailing date of this communication. e period for reply specified above is less than thirty (30) days, a reply period for reply is specified above, the maximum statutory period reto reply within the set or extended period for reply will, by staturely received by the Office later than three months after the mailined patent term adjustment. See 37 CFR 1.704(b).	136(a). In no event, howeve oly within the statutory minimu will apply and will expire SIX e, cause the application to be	r, may a reply be timely filed um of thirty (30) days will be considered to (6) MONTHS from the mailing date of the ecome ABANDONED (35 U.S.C. § 133).	
1)⊠	Responsive to communication(s) filed on 24	March 2003 .		
2a)⊠	This action is FINAL . 2b) ☐ T	his action is non-fina	I .	
3)	Since this application is in condition for allow closed in accordance with the practice under			the merits is
Disposit	ion of Claims			
4)⊠	Claim(s) <u>1,4-10,12-14 and 17-21</u> is/are pend	ing in the application		
	4a) Of the above claim(s) 7 and 8 is/are withd	rawn from considera	tion.	
5)	Claim(s) is/are allowed.			
_	Claim(s) <u>1,4-6,9,10,12-14 and 17-21</u> is/are re	jected.		
7)	Claim(s) is/are objected to.			
-	Claim(s) are subject to restriction and/	or election requireme	ent.	
· · · —	ion Papers			
·	The specification is objected to by the Examin		As hardha Faransinan	
10)	The drawing(s) filed on is/are: a) acce	•	•	->
11)	Applicant may not request that any objection to to the proposed drawing correction filed on			
٠٠/	If approved, corrected drawings are required in re			illiter.
12)	The oath or declaration is objected to by the E	• •		
	under 35 U.S.C. §§ 119 and 120			
_	Acknowledgment is made of a claim for foreig	n priority under 35 L	LS.C. § 119(a)-(d) or (f).	
	☐ All b)☐ Some * c)☐ None of:			
7.	1. Certified copies of the priority documen	ts have been receive	ed.	
	2. Certified copies of the priority documen			
* <u>\$</u>	Copies of the certified copies of the price application from the International Bee the attached detailed Office action for a lis	ority documents have ureau (PCT Rule 17.	e been received in this Nation 2(a)).	nal Stage
	Acknowledgment is made of a claim for domes	•		nal application)
-) The translation of the foreign language pr	•	•	na application).
_	Acknowledgment is made of a claim for domes			
Attachmen	t(s)			
2) Notice 3) Information	te of References Cited (PTO-892) te of Draftsperson's Patent Drawing Review (PTO-948) mation Disclosure Statement(s) (PTO-1449) Paper No(s)	5) 🔲 N	terview Summary (PTO-413) Paper otice of Informal Patent Application (her:	
I.S. Patent and T PTO-326 (Re		ction Summary	Part of Paper No	o. 7

Art Unit: 1763

DETAILED ACTION

Claim Rejections - 35 USC § 102

1. The following is a quotation of the appropriate paragraphs of 35 U.S.C. 102 that form the basis for the rejections under this section made in this Office action:

A person shall be entitled to a patent unless -

- (b) the invention was patented or described in a printed publication in this or a foreign country or in public use or on sale in this country, more than one year prior to the date of application for patent in the United States.
- 2. Claim 1 is rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent No. 5,256,204 to Wu.
- 3. Wu discloses a substrate processing apparatus successively transporting a substrate between a plurality of processing parts (Figure 2, 20) thereby performing a prescribed processing on said substrate, comprising: a transport robot (50; column 6, row 67 column 7, row 13) successively transporting said substrate between said plurality of processing parts along a prescribed procedure; and a plurality pf inspection parts (column 5, rows 31-37) of different contents respectively, provided in said substrate processing apparatus.
- 4. Examiner notes that the limitations drawn to the exact number of substrates transported to the inspection units are not structural limitations, but method limitations. The apparatus of Wu would be capable of transporting less than a whole set of processing parts to each of the inspection unit were the process sequence changed for any of the wafers (column 11, rows 26-31). The courts have ruled that a claim containing a "recitation with respect to the manner in which a claimed apparatus is intended to be employed does not differentiate the claimed apparatus from a prior art apparatus" if the prior art apparatus teaches all the structural limitations of the claim. Ex parte Masham, 2 USPQ2d 1647 (Bd. Pat. App. & Inter. 1987).
- 5. Claims 1 and 4-6 are rejected under 35 U.S.C. 102(b) as being anticipated by U.S. Patent No. 5,695,564 to Imahashi.

Art Unit: 1763

6. Imahashi discloses a substrate processing apparatus successively transporting a substrate between a plurality of processing parts (Figure 8; column 14, rows 6-11) thereby performing a prescribed processing on said substrate, comprising: a transport robot (U2a, U2b, U2c, U2d) successively transporting said substrate between said plurality of processing parts along a prescribed procedure; and a plurality pf inspection parts (U3a, U3d, U3c) of different contents respectively, provided in said substrate processing apparatus.

- 7. With respect to claim 4, a transport path (processing transport path proceeds form left to right in Figurer 8) is formed along said procedure and each of said plurality of inspection parts is arranged on an intermediate position in said transport path responsive to the inspection contents thereof.
- 8. With respect to claim 5, a processing condition may be changed in any of said plurality of processing parts on the basis of results of said inspection performed by said plurality of inspection parts (column 9, rows 24-28).
- 9. With respect to claim 6, the plurality of inspection parts include at least two of a resist thickness measuring part, a pattern line measuring part, a pattern overlay measuring part and a macro defect inspection part. Specifically, the prior art teaches inspection parts such as a thickness measuring part and a defect inspection (foreign matter testing device) (column 9, rows 12-25).
- 10. Examiner notes that the limitations drawn to the exact number of substrates transported to the inspection units are not structural limitations, but method limitations. The apparatus of Imahashi would be capable of transporting less than a whole set of processing parts to each of the inspection unit were the process sequence changed for any of the wafers (column 9, rows 25-28). The courts have ruled that a claim containing a "recitation with respect to the manner in which a claimed apparatus is intended to be employed does not differentiate the claimed apparatus from a prior art apparatus" if the prior art apparatus teaches all the structural limitations of the claim. Ex parte Masham, 2 USPQ2d 1647 (Bd. Pat. App. & Inter. 1987).

Art Unit: 1763

Claim Rejections - 35 USC § 103

- 11. The following is a quotation of 35 U.S.C. 103(a) which forms the basis for all obviousness rejections set forth in this Office action:
 - (a) A patent may not be obtained though the invention is not identically disclosed or described as set forth in section 102 of this title, if the differences between the subject matter sought to be patented and the prior art are such that the subject matter as a whole would have been obvious at the time the invention was made to a person having ordinary skill in the art to which said subject matter pertains. Patentability shall not be negatived by the manner in which the invention was made.
- 12. Claims 9, 12, 17 and 20 are rejected under 35 U.S.C. 103(a) as being unpatentable over U.S. Patent No. 5,256,204 to Wu in view of U.S. Patent No. 5,766,360 to Sato et al.
- 13. Wu discloses a substrate processing apparatus successively transporting a substrate between a plurality of processing parts (Figure 2, 20) thereby performing a prescribed processing on said substrate, comprising: a transport robot (50; column 6, row 67 column 7, row 13) successively transporting said substrate between said plurality of processing parts along a prescribed procedure; and a plurality of inspection parts (column 5, rows 31-37) of different contents respectively, provided in said substrate processing apparatus.
- 14. Wu also teaches that the apparatus may comprise plural "inspection machines" (column 5, rows 31-37).
- 14. Wu also discloses the substrate processing apparatus as comprising: a procedure setting part (carrier processor, column 11, rows 27-31) capable of incorporating substrate transportation to said inspection parts in an arbitrary order position in said procedure; and a transportation control part (vehicle computer, column 11, rows 31-35) controlling said transport part to successively transport said substrate along said procedure set by said procedure setting part.
- 15. However, fails to teach said procedure setting part capable of setting transport of each of part or all of a set of plural substrates to be subjected to the same processing to a single inspection unit selected

Art Unit: 1763

from said plurality of inspection parts, so that at least one and less than all of said set of plural substrates are transported to each of said plurality of inspection parts.

- 16. Sato et al. teach inspection of a sampling of a batch of processed wafers for the purpose of shortening the inspection time (column 4, row 52 through column 5, rows 3).
- 17. It would have been obvious to one of ordinary skill in the art at the time the Applicant's invention was made to have the procedure setting part set transportation of the substrates so that a sampling of a batch of substrates is transported to each processing unit in Wu in order to shorten the inspection time as taught by Sato et al.
- 18. With respect to claims 9 and 20, Wu further fails to teach the inspection part including a plurality of inspection contents.
- 19. Sato et al. further teach preparing a plurality of inspection units in an inspection chamber for the purpose of improving throughput of the inspections (column 5, rows 1-3).
- 20. It would have been obvious to one of ordinary skill in the art at the time the Applicant's invention was made to have provided a plurality of inspection units in each of the inspection chambers Wu in order to improved the throughput of the inspections as taught by Sato et al.
- 21. Claims 10, 13-14, 18-19 and 21 are rejected under 35 U.S.C. 103(a) as being unpatentable over Wu and Sato et al. as applied to claims 9, 12, 17 and 20 above, and further in view of U.S. Patent No. 6,313,903 to Ogata.
- 22. Wu and Sato et al. disclose the invention substantially as claimed and as described above.
- 23. However, the prior art fails to teach an apparatus, wherein each of said plurality of inspection parts is any of a thickness measuring part, a line width measuring part measuring the line width of a pattern, an overlay measuring part measuring overlay of said pattern and a macro defect inspection part, nor does Wu disclose any of said plurality of inspection parts is capable of performing resist film thickness measurement, pattern line width measurement and pattern overlay measurement.

Art Unit: 1763

Ogata discloses an inspection apparatus for inspection a resist pattern, comprising: a thickness measuring part measuring the thickness of a resist film, a line width measuring part measuring the line width of a pattern, an overlay measuring part measuring overlay of said pattern, a macro defect inspection part and other types of inspecting processes for the purpose of determining whether or not a resist pattern is acceptable (column 3, rows 16-19 and column 4, row 59 through column 5, row 25).

25. It would have been obvious to one of ordinary skill in the art at the time the Applicant's invention was made to have provided an inspection part capable of the claimed inspection processes in Wu in order to determine whether or not the resist pattern was acceptable as taught by Ogata.

Response to Arguments

- In response to applicant's argument that neither Wu, Ogata or Imahashi teach a method wherein not all tests are performed on all of the substrates, a recitation of the intended use of the claimed invention must result in a structural difference between the claimed invention and the prior art in order to patentably distinguish the claimed invention from the prior art (as noted above). If the prior art structure is capable of performing the intended use, then it meets the claim. In a claim drawn to a process of making, the intended use must result in a manipulative difference as compared to the prior art. See *In re Casey*, 152 USPQ 235 (CCPA 1967) and *In re Otto*, 136 USPQ 458, 459 (CCPA 1963).
- Additionally, Applicant argues that Imahashi fails to teach, "transporting the substrates in such a manner that assures that each inspection unit has at least one substrate form the plural substrates transported thereto under any and all conditions. As Applicant pointed out in the previous argument Imahashi does in fact teach transporting each of the substrates to all of the inspection units. This teaching would clearly encompass "transporting at least one substrate to each of the inspection units".

Conclusion

28. The prior art made of record and not relied upon is considered pertinent to applicant's disclosure.

* Application/Control Number: 09/942,153

Art Unit: 1763

29. Applicant's amendment necessitated the new ground(s) of rejection presented in this Office

action. Accordingly, THIS ACTION IS MADE FINAL. See MPEP § 706.07(a). Applicant is reminded of

the extension of time policy as set forth in 37 CFR 1.136(a).

A shortened statutory period for reply to this final action is set to expire THREE MONTHS from

the mailing date of this action. In the event a first reply is filed within TWO MONTHS of the mailing date

of this final action and the advisory action is not mailed until after the end of the THREE-MONTH

shortened statutory period, then the shortened statutory period will expire on the date the advisory action

is mailed, and any extension fee pursuant to 37 CFR 1.136(a) will be calculated from the mailing date of

the advisory action. In no event, however, will the statutory period for reply expire later than SIX

MONTHS from the date of this final action.

Any inquiry concerning this communication or earlier communications from the examiner should

be directed to Karla Moore whose telephone number is 703.305.3142. The examiner can normally be

reached on Monday-Friday, 8:30am-5:30pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's supervisor,

Gregory Mills can be reached on 703.308.1633. The fax phone numbers for the organization where this

application or proceeding is assigned are 703.872.9310 for regular communications and 703.872.9311 for

After Final communications.

Any inquiry of a general nature or relating to the status of this application or proceeding should be

directed to the receptionist whose telephone number is 703.308.0661.

km

June 6, 2003

GREGORY MILLS SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 1700 Page 7